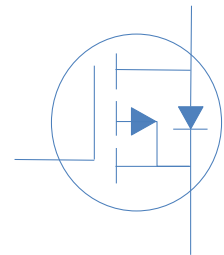
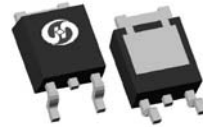




### 60V P-Ch Power MOSFET

			Ω
			Ω




=25 (unless otherwise specified)

		=25		
Avalanche Energy, Single Pulse	E			
Power Dissipation		=25		

Thermal Resistance Junction-Ambient		θ	W
Thermal Resistance Junction-Case		θ	W



**Electrical Characteristics at T =25 (unless otherwise specified)**

**Static Characteristics**

Drain to Source Breakdown Voltage		$\mu$				
Gate Threshold Voltage	$G_{S(th)}$	$\mu$				
		=25				$\mu$
		=125				
						$\Omega$
	$f_s$					
		=0V, f=1MHz				$\Omega$

**Dynamic Characteristics**

		=-25V, f=1MHz				pF
Reverse Transfer Capacitance						
Total Gate Charge						
Gate to Source Charge						
Gate to Drain (Miller) Charge						
Turn off Delay Time	$d(off)$	$\Omega$				
Fall Time	$f$					

**Reverse Diode Characteristics**

Diode Forward Voltage		$F$				
Reverse Recovery Charge		$F$	$f/dt=100A/\mu$			

Fig 1. Typical Output Characteristics

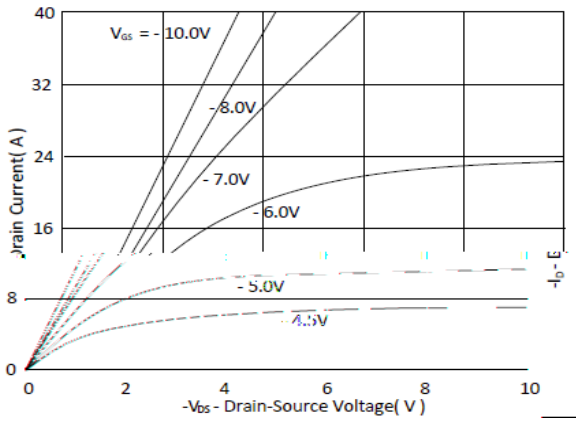


Figure 2. On-Resistance vs. Gate-Source Voltage

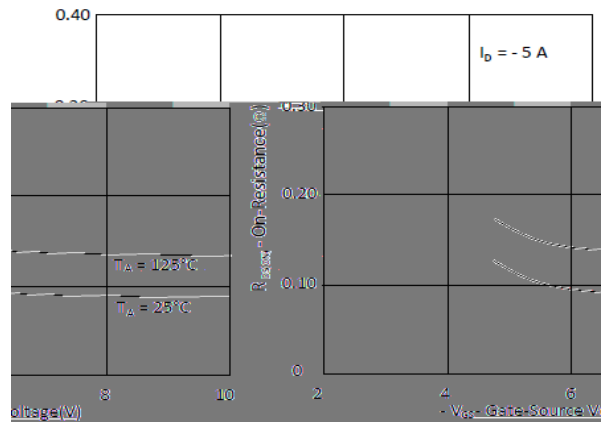


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

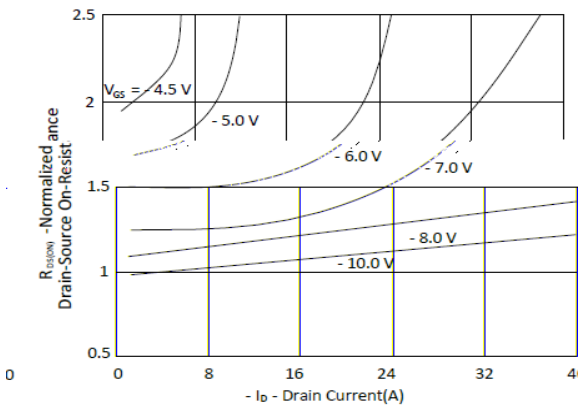


Figure 4. Normalized On-Resistance vs. Junction Temperature

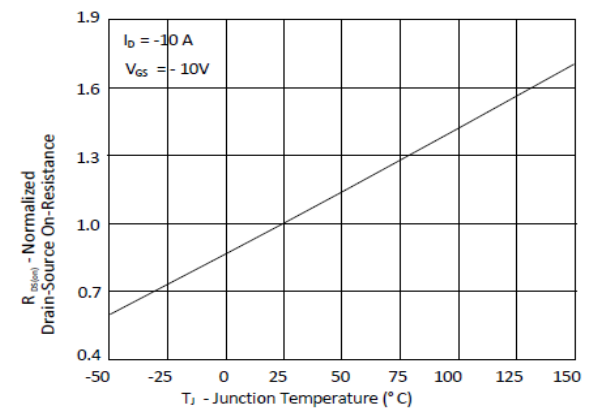


Figure 5. Typical Transfer Characteristics

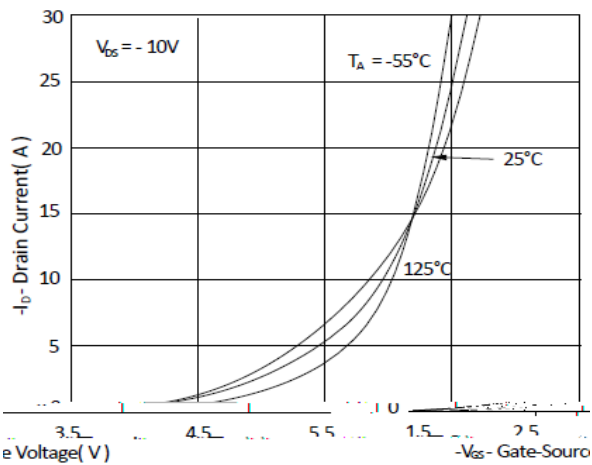


Figure 6. Typical Source-Drain Diode Forward Voltage

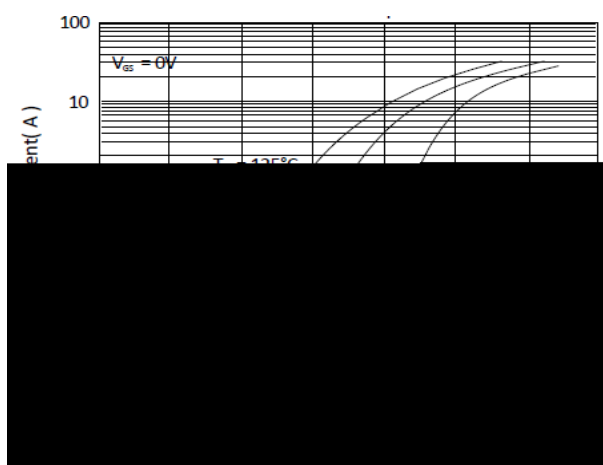
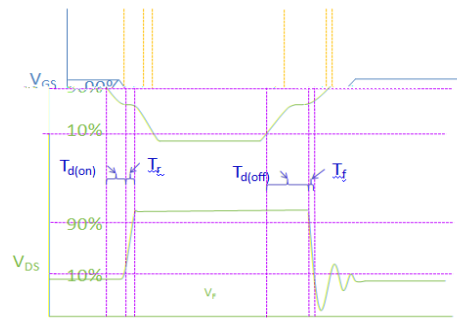
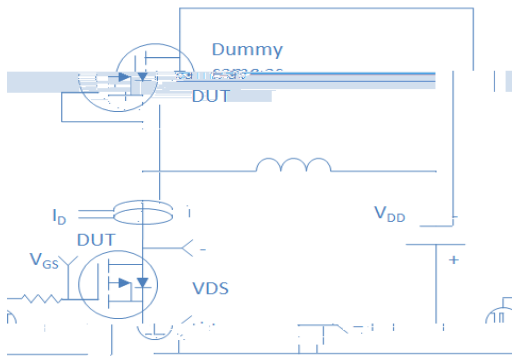


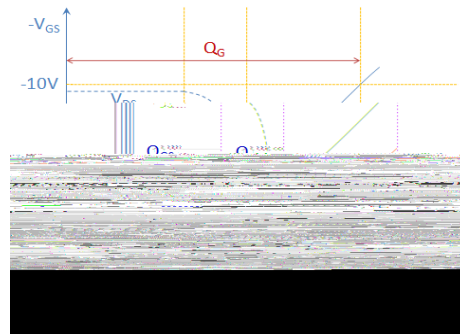
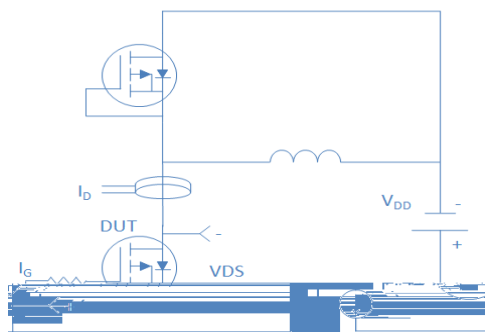


Figure 7. Typical Gate-Charge vs. Gate-to-Source Voltage

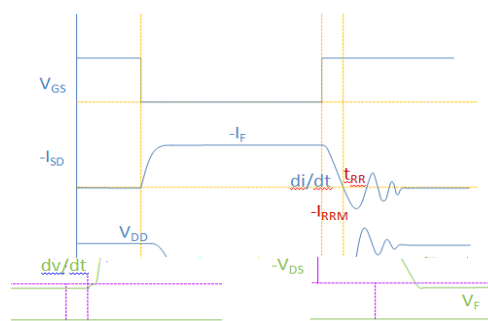
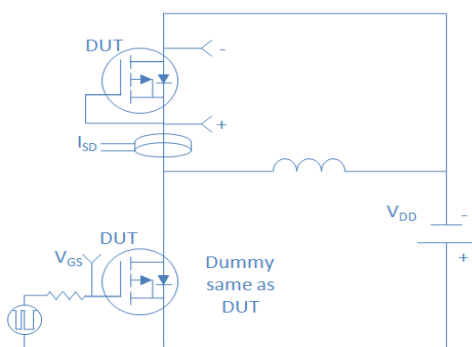
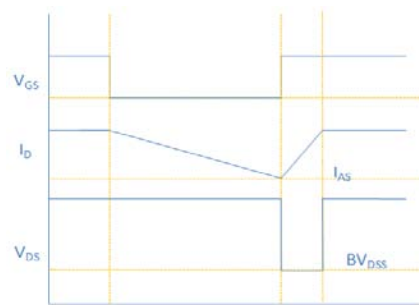
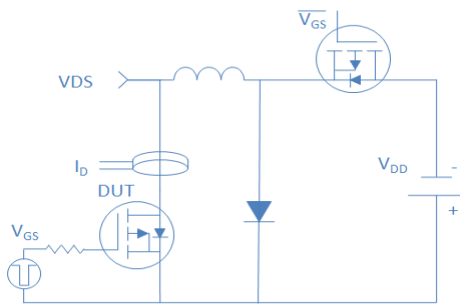
### Inductive switching Test

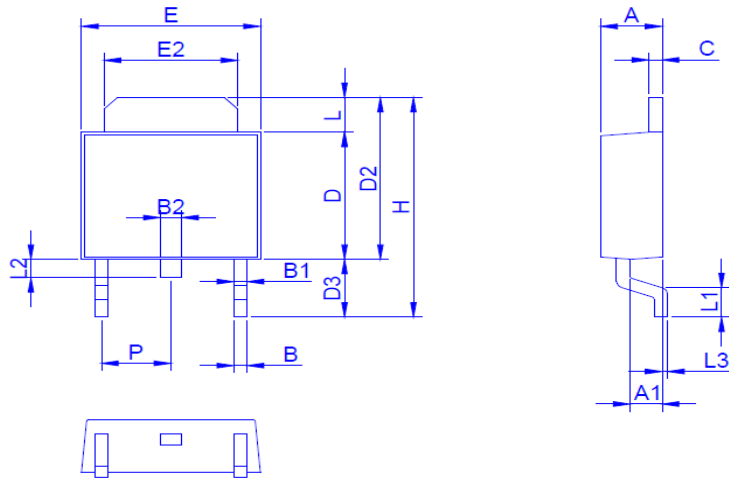


### Gate Charge Test



### Uclamped Inductive Switching (UIS) Test





Dimension	A	A1	B	B1	B2	C	D	D2	D3	E	E2	H	L	L1	L2	L3	P
0.60	0.40	5.30	6.70	2.20	6.40	4.80	9.20	0.89	0.90	0.50	0.00	2.10	Min.	2.10	0.95	0.30	0.40
1.00	0.60	6.20	7.30	3.00	6.70	5.45	10.15	1.70	1.65	1.10	0.30	2.50	Max.	2.50	1.30	0.85	0.94